

#### **Descriptions**

The NVT4557HKX device is built for interfacing a SIM card with a single low-voltage 1.0V to 1.8 V host side interface. The NVT4557HKX contains three 1.62 V to 3.6 V level translators to convert the data, RSTn and CLKn signals between a SIM card and a host microcontroller. The NVT4557HKX is compliant with all ETSI, IMT-2000 and ISO-7816 SIM/Smart card interface requirements.

#### **Order Information**

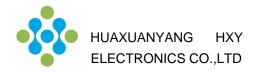
Package		Part Number	Top-Side Marking
QFN1418(XQFN-10(1.4x1.8))	Tape and Reel	NVT4557HKX	#####

#### **Features**

- Pin-to-Pin NVT4557 and NXT4557, both QFN1418(XQFN-10(1.4x1.8)) and CSP 1.2 x 1.2-9B
- Supports clock speed up to 10 MHz clock
- Compliant with all ETSI, IMT-2000 and ISO-7816 SIM/Smart card interface requirements
- Support SIM card supply voltages with range of 1.62 V to 3.6 V
- Host microcontroller operating voltage range: 1.08 V to 1.98 V
- Automatic level translation of I/O, RSTn and CLKn between SIM card and host side interface with capacitance isolation
- Incorporates shutdown feature for the SIM card signals according to ISO-7816-3
- Automatic enable and disable through VCCB (Enable pin on A4557 Q 10 pin package only)
- Integrated pull-up and pull-down resistors: no external resistors required
- Integrated EMI filters suppress higher harmonics of digital I/Os
- Integrated 8 kV ESD protection according to IEC 61000-4-2, level 4 on VCCB or any of the card side pins.
   External ESD diodes are not required.
- Level shifting buffers keep ESD stress away from the host (zero-clamping concept)
- Pb-free, Restriction of Hazardous Substances (RoHS) compliant and free of halogen and antimony (Dark Green compliant)
- Available in 9-pin WLCSP package in 0.3 mm pitch and 10-pin QFN10 package with 0.4mm pitch

## **Applications**

- Mobile, Smart phones and Wireless modems
- SIM card terminals



## **Functions and Pin Configuration**

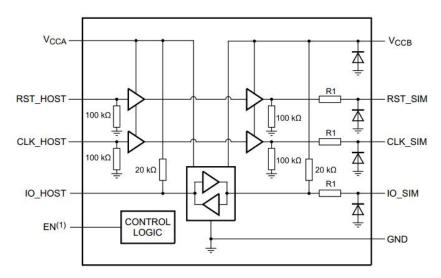


Fig.1 Functional Diagram

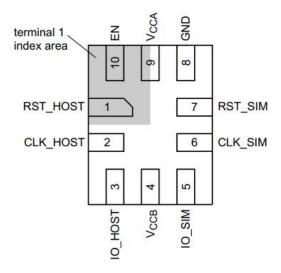


Fig.2 QFN1418(XQFN-10(1.4x1.8))

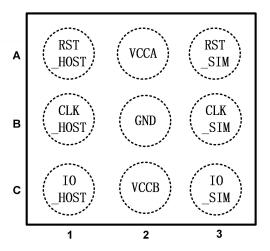


Fig.3 WLCSP 1.2x1.2 -9 Ball



### **Pin Descriptions**

Name	Pin for CSP	Pin for QFN	Туре	Description
RST_HOST	A1	1	I	Reset input from host controller
VCCA	A2	9	Supply	Supply voltage for the host controller side input/output pins (CLK_HOST, RST_HOST, IO_HOST). This pin should be bypassed with a 0.1 µF ceramic capacitor close to the pin.
RST_SIM	A3	7	0	Reset output pin for the SIM card
CLK_HOST	B1	2	I	Clock input from host controller
GND	B2	8	GND	Ground for the SIM card and host controller. Proper grounding and bypassing are required to meet ESD specifications
CLK_SIM	B3	6	0	Clock output pin for the SIM card
IO_HOST	C1	3	I/O	Host controller bidirectional data input/output. The host output must be on an open-drain driver
VCCB	C2	4	Supply	SIM card supply voltage. When VCCB is below the VCCBdisable, the device is disabled. This pin should be bypassed with a 0.1 µF ceramic capacitor close to the pin
IO_SIM	C3	5	I/O	SIM card bidirectional data input/output. The SIM card output must be on an open-drain driver
EN		10	I	Host controller driven enable pin. This pin should be HIGH (VCCA) for normal operation, and LOW to help avoid race conditions specifically during the shutdown sequence. (Only on 10 pin version - for 9 pin version EN is pulled to VCCA.)

**Table-1 Pin Descriptions** 

#### Shutdown Sequence of NVT4557HKX (10-pin version only)

The ISO 7816-3 specification specifies the shutdown sequence for the SIM card signals to ensure that the card is properly disabled for power savings. Also during hot swap, the orderly shutdown of these signals helps to avoid any improper write and corruption of data. When the enable, EN, is asserted LOW, the shutdown sequence is initiated by powering down the RST\_SIM channel. Once the RST\_SIM channel is powered down, CLK\_SIM and IO\_SIM are powered down sequentially one-by-one. An internal pull-down resistor on the SIM pins is used to pull these channels LOW. The shutdown sequence is completed in a few microseconds. It is important that EN is pulled LOW before VCCA and VCCB supplies go LOW to ensure that the shutdown sequence is properly initiated.

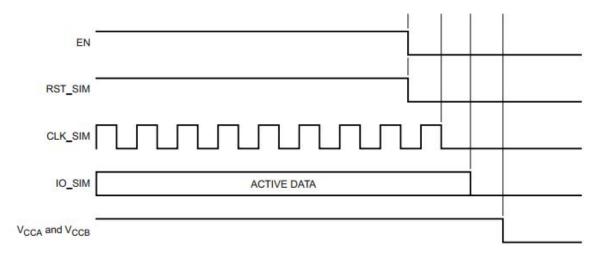


Fig.4 Shutdown sequence for RST\_SIM, CLK\_SIM, IO\_SIM and VCCA/VCCB

#### **Level Translator Stage**

The architecture of the device I/O channel is shown below. The device does not require an extra input signal to control the direction of data flow from host to SIM or from SIM to host. As a change of driving direction is just possible when both sides are in HIGH state, the control logic is recognizing the first falling edge granting it control about the other signal side. During a rising edge signal, the non-driving output is driven by a one shot circuit to accelerate the rising edge. In case of a communication error or some other unforeseen incident that would drive both connected sides to be drivers at the same time, the internal logic automatically prevents stuck-at situation, so both I/Os will return to HIGH level once released from being driven LOW. The channels RST and CLK just contain single direction drivers without the holding mechanism of the I/O channel, as these are just driven from the host to the card side.

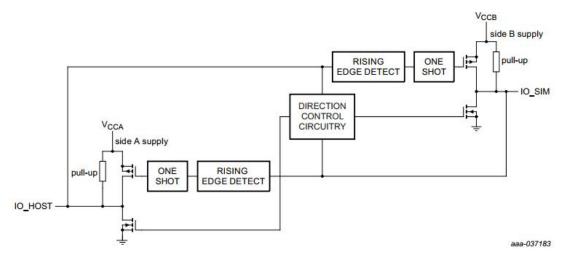
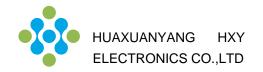


Fig.5 Automatic direction control level translator for HIGH-level direction change interfaces

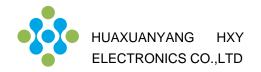


# **Electrical Characteristics** (Ta=25°C, V<sub>VCCA</sub> =1.0V~1.8V,V<sub>VCCB</sub> =1.62V~3.6V, unless otherwise specified)

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Power S	Supplies					•
VCCA	Host Side Supply		1.0		1.98	V
VCCB	SIM Side Supply		1.6		3.6	V
VVCCA_U VLO	VCCA Under Voltage Lockout	Rising, 100mV hysteresis	0.6	0.7	0.8	V
VVCCB_U VLO	VCCB Under Voltage Lockout	Rising. 100mV hysteresis	1.3	1.4	1.5	V
ISD_VCCA	Shutdown Current	VCCA=1.2V		0.5	1	uA
ISD_VCCB	EN=0V	VCCB=1.8V		0.5	1	uA
IQ_VCCA	Quiescent Current	VCCA=1.2V, CLK_HOST=0V		0.5	1	uA
IQ_VCCB	EN=VCCA	VCCB=1.8V, CLK_HOST=0V		0.5	1	uA
IACT_VCC A	Active Current	VCCA=1.2V, CLK_HOST=1MHz CL= 30pF		5	10	uA
IACT_VCC B	EN=VCCA	VCCB=1.8V, CLK_HOST=1MHz CL= 30pF		250	300	uA
Logic I/0	O pin (EN)					
ViH	High-Level Input Voltage	EN pin	0.7*VCCA			V
VIL	Low-Level Input Voltage	EN pin			0.3*VCC A	V
Level Tr	ranslator (Host Side					
VIH	High Level input voltage	IO_HOST, RST_HOST, CLK_HOST	0.7*VCCA			V
VIL	Low Level input Voltage	IO_HOST, RST_HOST, CLK_HOST			0.3*VCC A	V
Vон	High Level output voltage	IO_HOST, IOH_IO=20uA	0.8*VCCA			V
Vol	Low Level output voltage	IO_HOST, IOL_IO=20uA			0.2*VCC A	V
RPUA	Pull up resistance	IO_HOST connected to VCCA	6	8	10	kΩ
Level Tr	ranslator (SIM Card	Side)				
VIH	High Level input voltage	IO_SIM	0.7*VCCB			V
VIL	Low Level input Voltage	IO_SIM			0.3*VCC B	V
Vou l	High Level output	CLK_SIM, RST_SIM, IOH=20uA	0.8*VCCB			V
	voitage	IO_SIM, IOH=20uA	0.8*VCCB			V
Vol	Low Level output	CLK_SIM, RST_SIM, IOL =- 1mA			0.125* VCCB	V
	voltage	IO_SIM, IOL =-1mA			0.125* VCCB	V

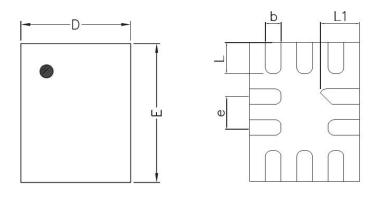
<b>R</b> РИВ	Pull up resistance	IO_SIM connected to VCCB	12	20	30	kΩ
Rs	Series resistance	IO_SIM, RST_SIM, CLK_SIM 40		55	100	Ω
RpD	Pull down resistance	IO_SIM, RST_SIM, CLK_SIM when EN is driven low		4		kΩ
Dynami	c Characteristics (CL	=30pE in Host side, CL=30Pf in	n SIM side, \	/CCA=1.	8V, VCCB	=3.0V)
tpp Propagation delay		From Host side to SIM side		10	20	ns
tpD	Propagation delay	From SIM side to HOST side		10	20	ns
	RST_SIM Rising time	From 10% to 90% of VCCB=3.0V		8	15	ns
tr_B CLK_SIM Ris	CLK_SIM Rising time	From 10% to 90% of VCCB=3.0V		8	15	ns
IO_SIM Rising time		From 10% to 90% of VCCB=3.0V		8	15	ns
tr_B RST SIM falling time CLK_SIM falling time IO_SIM falling time		From 90 %to 10% of VCCB=3.0V		8	15	ns
		From 90 %to 10% of VCCB=3.0V		8	15	ns
	IO_SIM falling time	From 90 %to 10% of VCCB=3.0V		8	15	ns
tr_A	IO_HOST rising time	From 10% to 90% of VCCA=1.8V		8	15	ns
tr_A	IO_HOST falling time	From 90 %to 10% of VCCA=1.8V		8	15	ns
ten	Enable timing	From EN High to RST_High			100	ns
trst_dis	RST_SIM Disable time	From EN Low to RST_SIM low		200		ns
tclk_dis	CLK_SIM Disable time	From EN low to CLK_SIM low		15		us
tio_dis	IO_SIM Disable time	From EN low to IO_SIM low				us
fclk	CLK_HOST frequency				10	MHZ

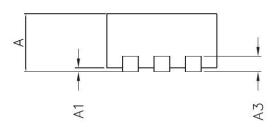
**Table-2 Electrical Characteristics** 



## **Package Outline Dimensions**

# QFN1418(XQFN-10(1.4x1.8))





Symbol	Dimension in Millimeters			
	Min.	Max.		
А	0.450	0.550		
A1	0.000	0.050		
A3	0.15	0.152 Ref.		
D	1.350	1.450		
E	1.750	1.850		
b	0.150	0.250		
е	0.40	0.400 Typ.		
L	0.350	0.450		
L1	0.450	0.550		



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